## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination FUJIWARA ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,577,631 B1	06-2003	Keenan et al.	370/394
*	В	US-2003/0076933 A1	04-2003	Ranalli et al.	379/88.17
*	С	US-6,549,534 B1	04-2003	Shaffer et al.	370/355
	۵	US-			
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-			
	1	US-			
	7	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 2001-54151	02-2001	Japan	Waseda et al	H04Q 3/58
*	0	WO 00/70845A1	11-2000	WIPO	Nilsson et al	H04M 1/274
*	Р	EP 1032224 A2	08-2000	European Patent	ROACH, PETER O JR	H04Q 7/24
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

	NON-PAIENT DOCUMENTS							
*	<u> </u>	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	V							
	w							
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.